



**SUBMIT AN ABSTRACT BY JULY 1**

**MARCH 14-18, 2021 • ORLANDO WORLD CENTER MARRIOTT  
ORLANDO, FLORIDA, USA  
[www.tms.org/TMS2021](http://www.tms.org/TMS2021) • #TMSAnnualMeeting**

**SUBMIT AN ABSTRACT TO:**

## **CHARACTERIZATION**

# **CHARACTERIZATION OF MATERIALS THROUGH HIGH RESOLUTION IMAGING**

This symposium will provide a venue for presentations regarding the use of coherent diffraction imaging techniques (x-ray and electron diffraction imaging, ptychography, holography) and phase contrast imaging techniques for high-resolution characterization in all classes of materials. Additionally, modeling and simulation methods that are relevant to nanoscale imaging techniques will be included.

## **ORGANIZERS**

**Ross Harder**, Argonne National Laboratory, USA  
**Richard Sandberg**, Brigham Young University, USA  
**Xianghui Xiao**, Brookhaven National Laboratory, USA  
**Saryu Jindal Fensin**, Los Alamos National Laboratory, USA

## **SYMPOSIUM SPONSORS**

TMS Structural Materials Division  
TMS Advanced Characterization, Testing, and Simulation Committee

**Abstract Deadline is July 1, 2020. Submit online at  
[www.programmaster.org/TMS2021](http://www.programmaster.org/TMS2021).**

**Questions?**  
Contact [programming@tms.org](mailto:programming@tms.org)